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Summer 2012

FOURTH ENGINEERING (ELECTRICAL & ELECTRONIC)

Digital IC Design UE4001

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Answer Question 1 and two of the remaining three questions 3 HOURS

Approved Calculator Allowed

Questions follow overleaf

- a) Describe the following terms: structural design; synthesis; system level design; algorithm complexity; asynchronous design.
- b) Present the average energy dissipation due to charging and discharging of capacitive loads in the context of a digital Integrated Circuit.
- c) Describe the implementation of an 8-bit parity checker and optimise it for speed using associative transformations and pipelining. Discuss your options.
- d) Draw the gate level schematic of a one-bit adder and discuss its transistor complexity.
- e) Implement the following logic function F using two-input NAND gates (and inverters respectively) as well as a 4 input complex gate (AOI gate):

F= NOT((IN1 AND IN2) OR (IN3 AND IN4))

Draw the corresponding transistor diagrams.

- f) Define the following: cycles per data item; longest path delay; data throughput; latency; size time product; energy per data item.
- g) Given the circuits in figure 1, discuss the setup and hold times for balanced distribution delays and in the presence of skew.

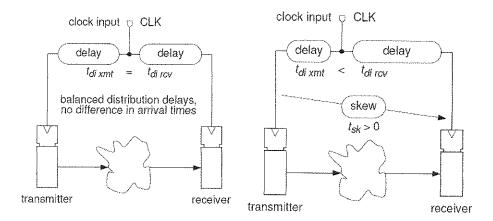


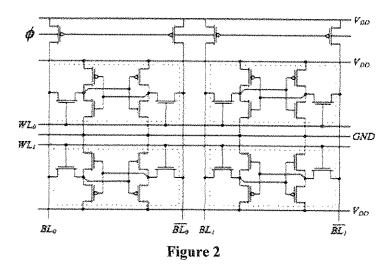
Figure 1

h) Describe two on-chip clock distribution schemes. For the on-chip interconnect, derive the propagation delay using a single buffer and multiple buffers/repeaters.

Ouestion 2 [30 marks]

i) Explain the main architectural differences between SRAM and DRAM memories and the relevant performance (speed and power) trade-off. (5 marks)

ii) A part of a memory with four memory cells, highlighted with the dotted lines, is shown in Figure 2.



- a. What type memory cell is it? Justify your answer. (3 marks)
- b. What purpose do the four transistors at the top have? (2 marks)
- c. Describe the procedure for writing a word into the memory. (5 marks)
- d. Describe the procedure for reading a word from the memory. (5 marks)
- iii) Describe the architecture and functionality of a latch. (10 marks)

Question 3 [30 marks]

For the circuit in Figure 3 assume a unit delay through the register and logic blocks $(t_R=t_L)$. Assume that the registers, which are positive edge triggered, have a set-up time t_S of 1. The delay through the multiplexer t_M is 2 t_R .

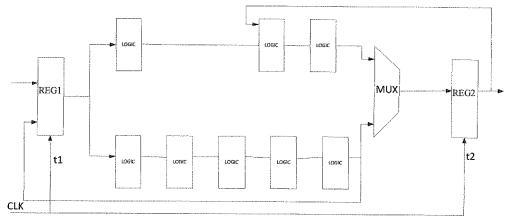


Figure 3

- a) Assuming that the clock skew is zero, determine the minimum clock period of the circuit. (10 marks)
- b) What is the minimum period of CLK if the clock skew is $t_{sk}=t_2-t_1=4?(10p)$
- c) Given that the area of logic blocks is expressed as AL times 2 input XOR gates, area of the register is AR times 3 input NOR gates and area of multiplexer is AMUX times 2 input NAND gates, what is the complexity of the circuit expressed in terms of two input NAND gates (gate equivalents) and the total number of transistors.(10p)

Question 4 [30 marks]

a) Given the waveforms in Figure 4, describe in VHDL (or Verilog) the corresponding testbench which would generate them. CLK, A1 and A2 are input signals to an abstract block given by:

VHDL

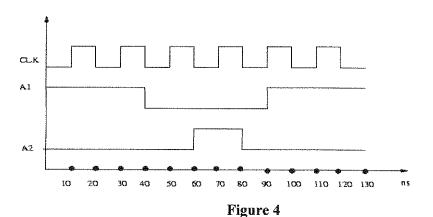
entity block_A(CLOCK, A_ONE, A_TWO: in std_logic, OTP: out
std_logic_vector(3 downto 0));
or

Verilog

module block_A (CLOCK, A_ONE, A_TWO, OTP);

What is the clock frequency? The time units are in nano seconds. (10marks)

b) Describe in VHDL the architecture (or Verilog module) of an entity/block for which OTP is the output of a 4 bit up-down counter with an active high reset A_TWO and up-down signal is given by A_ONE (=1 for count up, 0 for count down). Present the sequence for the counter assuming that at time 0, OTP is 3. (10 marks)



c) Present the schematic (block or RTL level) of the 4-bit up down counter by presenting the constituent blocks and associated gate complexity. (10 marks)